Search Notes			
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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/080,795	KAMME ET AL.	
Examiner	Art Unit	
Young J. Kim	1637	

SEARCHED			
Class	Subclass	Date	Examiner
435	6	6/6/2005	YJK
	91.1	6/6/2005	YJK
	91.2	6/6/2005	YJK

	INTERFERENCE SEARCHED			
	Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)	6/6/2005	YJK
STN Commercial Databases (Biosis, Medline, Embase, Embal, SciSearch, CAPlus)	6/6/2005	YJK
See enclosed for search strategies	6/6/2005	YJK